

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/705,935	KAMIJIMA, SHUNJI	
		Examiner	Art Unit	
		Jason M Han	2875	Page 1 of 4

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		Jason M Han	2875	

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		Examiner	Art Unit	Page 4 of 4
		Jason M Han	2875	

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